

Coverage based Test Generation for Duration Systems

Maha Naceur, Lotfi Majdoub and Riadh Robbana

LIP2 Laboratory, Faculty of Sciences of Tunis, Tunis, Tunisia

Abstract. In this paper, we are interested in generating test cases for duration systems with respect to coverage criteria. Duration systems are an extension of real-time systems for which delays that separate events depend on the accumulated times spent by the computation at some particular locations of the system. We present a test generation method for duration systems by considering coverage criteria. This method uses the approximation approach and extends a model using an over approximation, the approximate model, containing the digitization timed words of all the real computations of the duration system. Then, we propose an algorithm that generates a set of test cases presented with a tree by considering a discrete time and respecting a coverage criterion in order to select test cases.

1 Introduction

Testing is an important validation activity that aims to check whether an implementation, referred to as an Implementation Under Test (IUT), conforms to its specification. The testing process is difficult, expensive and time-consuming. A promising approach to improve testing consists in automatically generating test cases from formal models of specification. Using tools to automatically generate test cases may reduce the cost of the testing process.

In this work, we are interested in testing duration systems. Duration systems are an extension of real-time systems for which, in addition to constraints on delays separating certain events that must be satisfied, constraints on accumulated times spent by computation must also be satisfied. Timed automata constitute a powerful formalism widely adopted for modeling real-time systems [2]. Duration Variables Timed Graphs with Inputs Outputs (DVTG- IOs) are an extension of timed automata [3], which are used as a formalism to describe duration systems. DVTG- IOs are supplied with a finite set of continuous real variables that can be stopped in some locations and resumed in other locations. These variables are called duration variables.

For testing real-time systems, most works borrow several techniques from the real-time verification field due to similarities that exist between model-based testing and formal verification (e.g., symbolic techniques, region graph and its variations, model checking techniques, etc.). Those techniques are used particularly to reduce the infinite state space to a finite or countable state space. Then they adapt the existing untimed test case generation algorithm. We cite as examples [6][8][9]. It is well known that the verification of real-time systems is possible due to the decidability of the reachability

problem for real-time systems [1]. However, it has been shown that the reachability problem is undecidable for timed graphs extended with one duration variable [5] and, consequently, it is not possible to use classical verification techniques to generate test cases for DVTG-IO.

We give in this paper a method for generating test cases with respect to coverage criteria for duration systems. In practice, Complete test cases cannot be performed in a finite time. This implies that a strategy of test selection should be done to choose the adequate test cases to be applied in the implementation under test. Coverage criteria are a measure allowing to select test cases according to some criteria. Different coverage criteria have been proposed such as statement coverage, branch coverage and so on [17]. Here, we propose a technique to select test cases according to state coverage criterion and transition criterion.

Formally, we describe the specification as well as the implementation under test with DVTG-IO. In order to reduce the infinite state space to a finite state space, we use the approximation method that extends a given DVTG-IO specification to another called the approximate model that contains the initial test cases as well as their digitizations. An algorithm for generating a set of test cases, satisfying a coverage criterion, is given. We present this set of test cases by a tree.

This paper is organized as follows: In the next section, we present the duration variables timed graphs with inputs outputs. In section 3, we present the approximation method. Section 4 shows our testing method for generating tests with respect to coverage criteria. Section 5 gives conformance relation to show that the generated test cases are sound. Concluding remarks are presented in section 6.

2 Duration Variables Timed Graphs with Inputs Outputs

A DVTG-IO is described by a finite set of locations and a transition relation between these locations. In addition, the system has a finite set of duration variables that are constant slope continuous variables, each of them changing continuously with a rate in $\{0,1\}$ at each location of the system. Transitions between locations are conditioned by arithmetical constraints on the values of the duration variables. When a transition is taken, a subset of duration variables should be reset and an action should be executed. This action can be either an input action, an output action or an unobservable action [16].

2.1 Formal Definition

We consider X a finite set of duration variables. A guard on X is a boolean combination of constraints of the form $x \prec c$ where $x \in X$, $c \in \mathbb{N}$, $\prec \in \{<, \leq, >, \geq\}$. Let $\Gamma(X)$ be the set of guards on X . A DVTG-IO describing duration systems is a tuple $S = (Q, q_0, E, X, Act, \gamma, \alpha, \delta, \vartheta)$ where :

- Q is a finite set of locations,
- q_0 is the initial location,
- $E \subseteq Q \times Q$ is a finite set of transitions between locations,
- $Act = Act_{In} \cup Act_{Out} \cup \{\tau\}$ is a finite set of input actions (denoted by $?a$), output

actions (denoted by $!a$) and unobservable action ξ ,

- $\gamma : E \longrightarrow \Gamma(X)$ associates to each transition a guard which should be satisfied by the duration variables whenever the transition is taken,
- $\alpha : E \longrightarrow 2^X$ gives for each transition the set of duration variables that should be reset when the transition is taken,
- $\delta : E \longrightarrow Act$ gives for each transition the action that should be executed when the transition is taken,
- $\partial : Q \times X \longrightarrow \{0, 1\}$ associates with each location q and each duration variable x the rate at which x changes continuously in q .

Example. To illustrate DVTG-IO, we show on Fig.1 the specification of a vending machine. This machine delivers a beverage after receiving a coin from the user. It is composed of locations $\{q_0, q_1, q_2, q_3, q_4, q_5\}$ where q_0 is the initial location, transitions between locations and is supplied with a set of input actions $\{?choose, ?coin\}$, output actions $\{!price, !accept, !deliver, !returncoin, !return, !timeout\}$ and three duration variables x, y, z . Duration variables x and y are clocks used to make constraints on the time execution of the vending machine, z is a duration variable, it is stopped in q_0, q_2 and it is used to make constraints on the time spent by the system. The behavior of this machine can be describes as follows:

- In the initial node q_0 , the system waits for the user to choose a beverage. The user can decide his choice during a time unit.
- In the node q_1 , the machine tells the user the price of the drink chosen and pass to the node q_2 .
- In the node q_3 , the machine checks the coins; if they are accepted, it enters the node q_4 and provides the drink, otherwise it returns coins and passes to q_0 .

2.2 State Graph

The semantic of DVTG-IO is defined in terms of a state graph over states of the form $s = (q, \nu)$ where $q \in Q$ and $\nu : X \longrightarrow \mathbb{R}^+$ is a valuation function that assigns a real value to each duration variable. Let St_S be the set of states of S . We notice that St_S is an infinite set due to the value of duration variables taken on \mathbb{R}^+ . A state (q, ν) is called integer state if $\nu : X \longrightarrow \mathbb{N}$. We denote by $N(St_S)$ the set of integer states of S .

Given a valuation ν and a guard g , we denote by $\nu \models g$ the fact that valuation of g under the valuation ν is true.

We define two families of transition between states : discrete transition $(q, \nu) \xrightarrow{a} (q', \nu')$ with $(q, q') \in E$, $\delta(q, q') = a$, $\nu \models \gamma(q, q')$ is true and $\nu'(x) = \nu(x) \forall x \in X \setminus \alpha(q, q')$, $\nu'(x) = 0 \forall x \in \alpha(q, q')$, that corresponds to moves between locations using transition in E ; timed transition $(q, \nu) \xrightarrow{t} (q, \nu')$ such that $t \in \mathbb{R}^+$ and $\nu'(x) = \nu(x) + \partial(q, x) * t \forall x \in X$, that corresponds to transitions due to time progress at some location q . The state graph associated with S is (St_S, \hookrightarrow) where \hookrightarrow denotes the union of all discrete and timed transitions.

2.3 Computation Sequences and Timed Words

A Computation sequence of a DVTG-IO is defined as a finite sequence of configurations. A configuration is a pair (s, τ) where s is a state and τ is a time value. Let C_S be

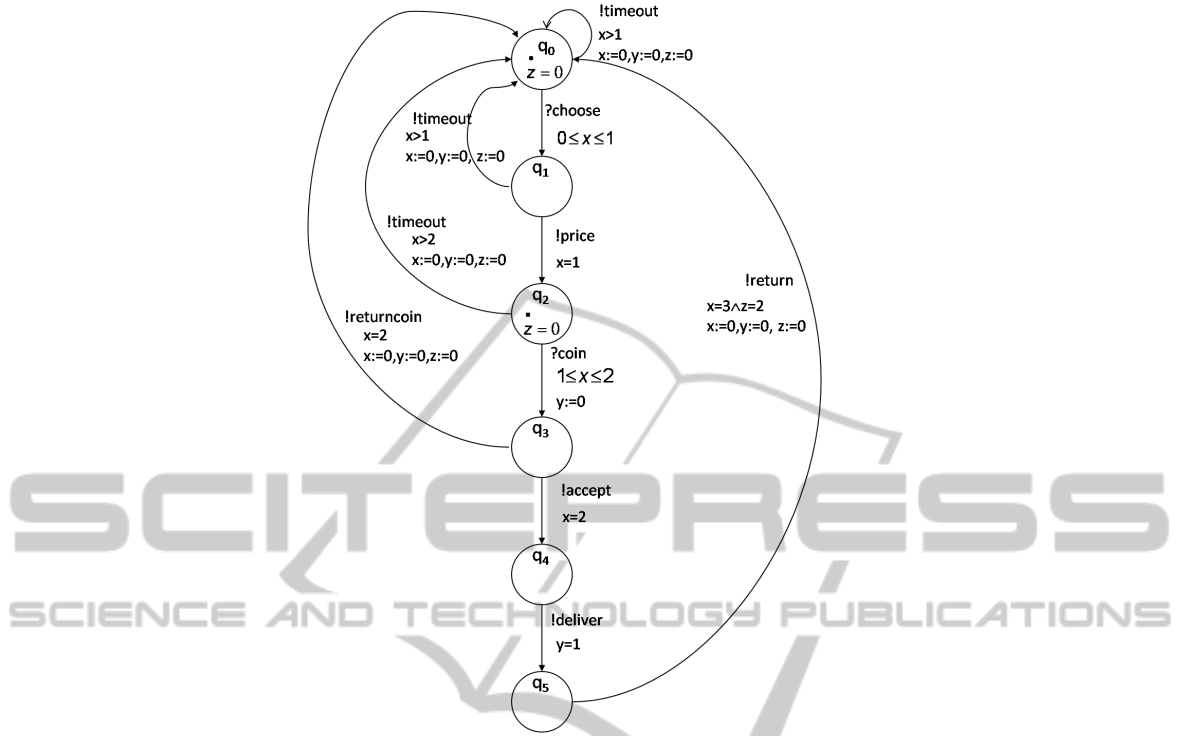


Fig. 1. DVTG-IO of a vending machine.

the set of configurations of S . Intuitively, a computation sequence is a finite path in the state graph of an extension of S by an observation clock that records the global elapsed time since the beginning of the computation.

Formally, if we extend each transition relation from states to configurations, then a computation sequence of S is $\sigma = (s_0, 0) \rightsquigarrow (s_1, \tau_1) \rightsquigarrow \dots \rightsquigarrow (s_n, \tau_n)$, where $s_i = (q_i, \nu_i)$ and $\tau_{i-1} \leq \tau_i$ for $i = 1..n$. Let $CS(S)$ be the set of computation sequences of S . A timed word is a finite sequence of timed actions. A timed action is a pair $a\tau$ where $a \in Act$ and $\tau \in \mathbb{R}^+$, meaning that action a takes place when the observation clock is equal to τ . A timed action $a\tau$ is called integer timed action if $\tau \in \mathbb{N}$. A timed word is a sequence $\omega = a_1\tau_1 a_2\tau_2 \dots a_n\tau_n$ where a_i is an action and τ_i is a value of the observation clock. We notice that $\tau_i \leq \tau_{i+1}$. Let $L(S)$ be the set of timed words of S . A sequence $\omega = a_1\tau_1 a_2\tau_2 \dots a_n\tau_n$ is considered a timed word of $L(S)$ if and only if there exists a computation sequence $\sigma = (s_0, \tau_0) \rightsquigarrow (s_1, \tau_1) \rightsquigarrow \dots \rightsquigarrow (s_n, \tau_n) \in CS(S)$ such that $a_i = \delta(q_{i-1}, q_i)$ for $i = 1, \dots, n$ and $s_i = (q_i, \nu_i)$. For simplicity, we may write $(s_0, \tau_0) \rightsquigarrow^\omega (s_n, \tau_n)$.

Let $\omega = a_1\tau_1 a_2\tau_2 \dots a_n\tau_n$ be a timed word and $a \in Act$, $\tau \in \mathbb{R}$ such that $\tau_n \leq \tau$ then we denote by $\omega.a\tau$ the timed word obtained by adding $a\tau$ to ω and we have $\omega.a\tau = a_1\tau_1 a_2\tau_2 \dots a_n\tau_n a\tau$.

3 Approximation

The approximation method is used in the verification of duration systems [14]. It allows to reduce the infinite set of states to a finite set. We adapt this method to test duration systems.

3.1 Digitization

We present the notion of digitization [7], which is suitable for the systems in which we are interested. Let $\tau \in \mathbb{R}^+$. For every $\epsilon \in [0, 1[$, called digitization quantum, we define the digitization of $[\tau]_\epsilon = \lfloor \tau \rfloor$ if $\tau \leq (\lfloor \tau \rfloor + \epsilon)$ else $[\tau]_\epsilon = \lceil \tau \rceil$.

Given $\epsilon \in [0, 1[$, the digitization of a timed word $\omega = a_1\tau_1a_2\tau_2\dots a_n\tau_n$ is $[\omega]_\epsilon = a_1[\tau_1]_\epsilon a_2[\tau_2]_\epsilon \dots a_n[\tau_n]_\epsilon$.

Therefore, it is not difficult to see that: $[\omega.at]_\epsilon = [\omega]_\epsilon.a[t]_\epsilon$. Moreover, it is easy to relate digitizations of a computation sequence and its timed word. If σ is a computation sequence and ω is its corresponding timed word then for $\epsilon \in [0, 1[$, $[\omega]_\epsilon$ is the corresponding timed word of $[\sigma]_\epsilon$. We denote by $Digit(L(S))$ the set of all the digitizations of all the real timed word of S . We notice that $Digit(L(S))$ is countable. The digitization is used to reduce the infinite set of states to a finite set of states. A question that one may ask is whether $Digit(L(S)) \subseteq L(S)$ or not.

3.2 Approximate Model

As we have seen in the previous example, some timed words of a DVTG-IO do not have any digitizations in S . The idea given in [14] consists of over approximating the model S by an approximate model S' such that $Digit(L(S)) \subseteq L(S')$.

Definition 1: The function $\beta : X \times E \rightarrow \mathbb{N}$ calculates for each variable $x \in X$ and each transition $e = (q, q')$ the maximum of restarts of x from the last reset of x until the location q in each way.

A restart of a variable x is the change of its rate from 0 to 1. After a reset of a variable x , if the rate of a variable x in the current location is 1, then the access to this location is considered as a restart of x . That is why, for the clocks, the function β is equal to 1 for each transition.

Definition 2: The approximate model $S' = App(S)$ is obtained from S by transforming each guard of a transition e of the form $u \prec y \prec w$ by the guard:

If $u - \beta(y, e) \geq -1$ then $u - \beta(y, e) + 1 \leq y \leq w + \beta(y, e) - 1$ else $0 \leq y \leq w + \beta(y, e) - 1$ where $u, w \in \mathbb{N}$, $x \in X$, $et \prec \in \{<, \leq\}$.

Proposition 1: $\forall \omega \in L(S)$ we have $[\omega]_\epsilon \in L(S')$ for each $\epsilon \in [0, 1[$.

This proposition demonstrates that for every timed word of the specification model, its digitizations belong to the approximate model.

Example. If we apply the approximation method on the DVTG-IO of the Fig.1, we obtain the approximate model on the Fig.2. It involves replacing the guard $x=3 \wedge z=2$ associated with the transition (q_5, q_0) with the guard $x=3 \wedge 1 \leq z \leq 3$ because we have $\beta(z, (q_5, q_0)) = 2$

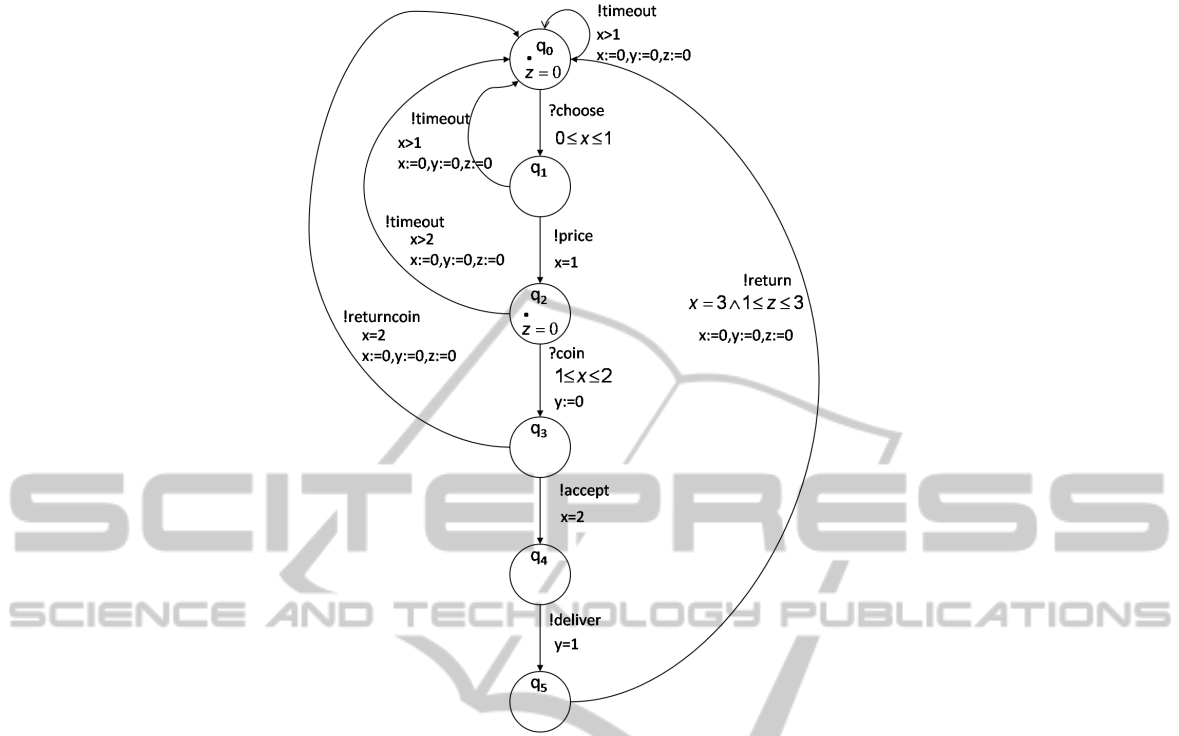


Fig. 2. The approximate model of a vending machine.

3.3 Test Generation with the Approximate Model

First, let us introduce the notion of an observation which is a sequence of controllable (inputs) and observable (outputs) actions that are either executed or produced by the IUT followed by its occurrence time. Formally, we describe an observation by a timed word $\omega = a_1\tau_1 a_2\tau_2 \dots a_n\tau_n$ where $a_i \in Act$ and $\tau_i \in \mathbb{R}^+$ for $i = 1..n$.

Our result is based on a reduction of the infinite state graph associated with $S' = App(S)$ to the countable state graph $(N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$, where the space of states is the set of integer states. Transitions between states are either discrete transition $(q, \nu) \overset{a}{\rightsquigarrow} (q', \nu')$ labeled with action in Act , or timed transition $(q, \nu) \overset{1}{\rightsquigarrow} (q', \nu')$ labeled with a constant delay of time equal to 1. Notice that ν and $\nu' \in [X \rightarrow \mathbb{N}]$. Clearly, the digitizations of all timed words $Digit(L(S))$ are included in $(N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$.

We define a number of operators that we use in the algorithm of generating test tree.

Let C be a configuration of $(N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$ and $a\tau$ is timed action.

$Out(C)$ (resp. $In(C)$) is the set of all timed output actions (resp. the set of all timed input actions) that can occur when the system is at configuration of C . Furthermore, C after $a\tau$ is the set of all configurations that can be reached from C after the execution of the timed word $a\tau$. Notice that $Out(C)$, $In(C)$ and C after $a\tau$ are finite sets. They are calculated in $(N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$.

3.4 The Test Tree

We use the countable state graph $(N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$ to generate a finite set of test cases. This set of test cases is represented by a tree called Test Tree. The test tree is composed by nodes that are sets of integer configurations and transitions between those nodes. A node in the test tree is a finite set of integer configurations (s, τ) such that $s \in (N(St_{S'}))$, $\tau \in \mathbb{N}$ and represents the possible current integer configurations of the IUT. The root is the initial configuration of $(N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$ that is (s_0, τ_0) .

The transition between one node and its successor is labelled with a timed action $a\tau$ such that $a \in Act$ and $\tau \in \mathbb{N}$. A path from the root to one leaf of the tree represents a digitization of a timed word.

Example. An example of test tree is given in fig.3. It is constructed from the approximate model of fig.2. Each path of the test tree from the root to a leaf corresponds to an integer computation sequences of the approximate model. Notice that is a complete test tree, it contains all possible integer test cases belonging to the approximate model.

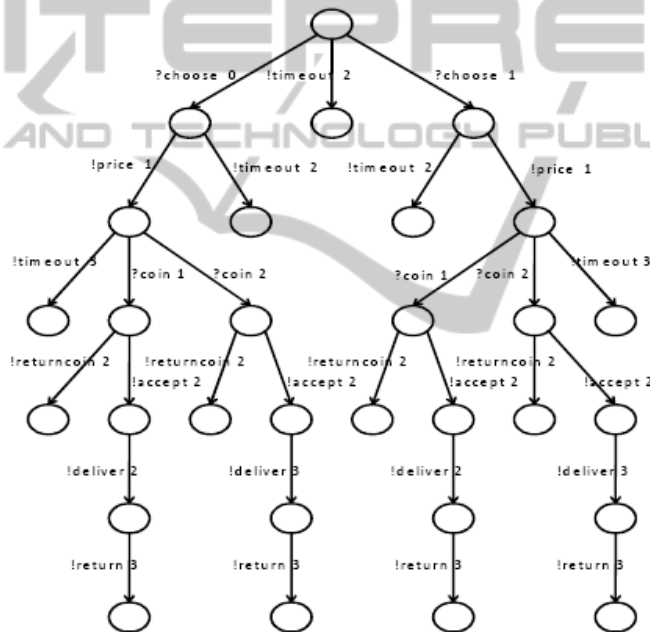


Fig. 3. The test tree.

4 Generating Tests with Respect to Coverage Criteria

Here, we introduce our approach to generating test cases for duration systems that is based on the approximation method and with respect to coverage criteria.

4.1 Coverage Criteria

In practice, generating a complete test case cannot be executed in a finite time. The aim

of the tester is to generate a set of test cases that cover the state graph of the specification model.

This implies that the tester should apply a strategy of test selection that allows to choose the adequate test cases to be applied on the implementation under test. Coverage criteria are a measure used to select test cases according to some criteria. A large suite of coverage criteria has been proposed in the literature. Different coverage criteria have been proposed such as location coverage, edge coverage and so on [16].

We present here two types of coverage criteria that we use to select test cases from the state graph of a DVTG-IO model:

- State coverage : A set of test cases satisfies the state coverage criterion if, when executed on the model, they visit every state of the state graph model. In other words, every state is covered by some test case. Notice that the set of states is infinite. A set of test cases covering states also covers transitions. However, it may not cover all transitions of the model.
- Transition coverage : test cases satisfy the transition coverage criterion if, when executed on the model, they traverse every transition of the specification model. We can distinguish here between discrete transition and timed transition.

4.2 Algorithm of Coverage Generating Test Tree

We adapt the test generation algorithm of [13] in order to select test cases. The following algorithm considers only the test cases that satisfy the coverage criteria. These test cases are represented by a test tree. The coverage criterion considered in this algorithm is the state coverage of the state graph of the approximate model.

Algorithm 1: Coverage Generating Test Tree.

```

1  Input :  $N(G_{S'}) = (N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$ 
2  Output : Test Tree T
3   $T = T' = \{(s_0, 0)\}$  the one-node tree
4  while  $T' \neq T$ 
5     $T := T'$ 
6    for each leaf  $C$  of  $T$  distinct from pass
7       $Out(C) ; In(C)$ 
8      if  $Out(C) \cup In(C) = \emptyset$  then
9         $C = pass$ 
10     else
11       for each  $a\tau \in Out(C) \cup In(C)$ 
12          $C' = C$  after  $a\tau$ 
13         if not exist( $C', T'$ )
14           append edge  $C \overset{a\tau}{\rightsquigarrow} C'$  to  $T$ 
15 End while
16 End
```

The coverage generating test tree algorithm operates as follows : initially the test tree contains one node that is the initial configuration of $S' : (s_0, 0)$. For every leaf C of the tree distinct from *pass*, the algorithm calculates the set of integer timed actions ($In(C)$ and $Out(C)$) that can be taken when the system is in C . For each timed action

$a\tau$ belonging to $Out(C) \cup In(C)$ the algorithm calculates $C' = C$ after $a\tau$, the set of configurations obtained when $a\tau$ is executed.

The edge $C \xrightarrow{a\tau} C'$ is appended to the test tree if C' does not belong to the test tree. The algorithm can stop branching a path of the tree by appending the node pass in the leaf that has not any timed action ($In(C) \cup Out(C) = \emptyset$).

Example. To illustrate the above algorithm, we consider the approximate model of the vending machine. A possible test tree, respecting the state coverage criterion, is given in fig.4.

However, it is not difficult to replace this criterion with transition coverage. An algorithm was also implemented to generate test cases respecting the coverage of transitions. In this algorithm, the transition $C \xrightarrow{a\tau} C'$ is added to the tree test if C' does not already exist.

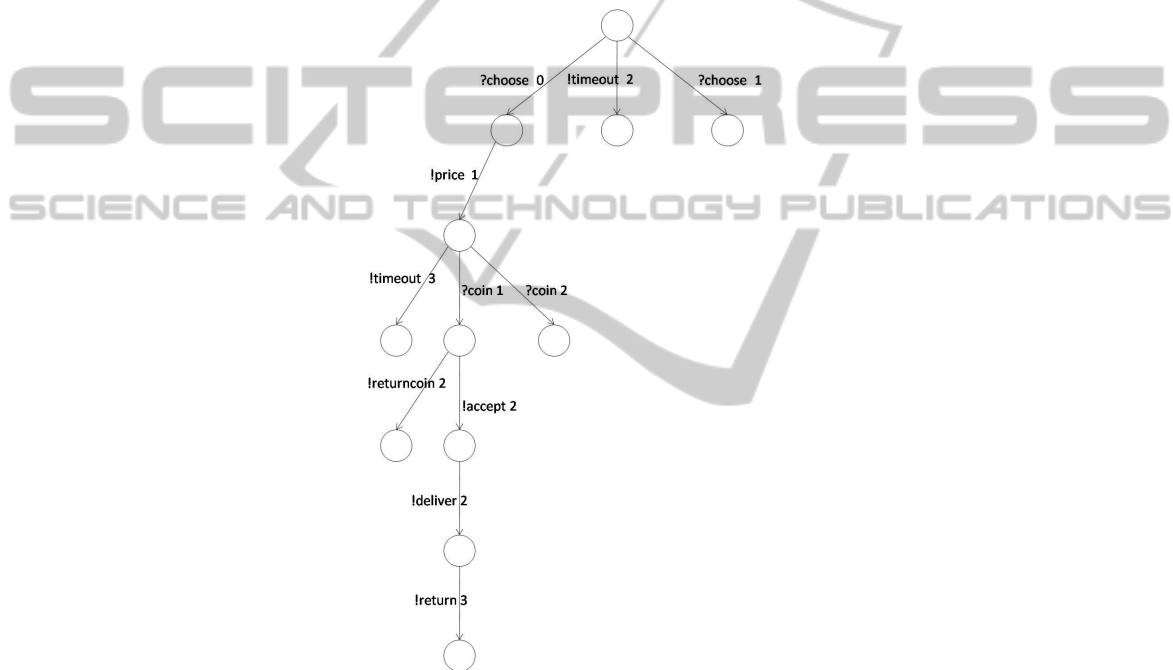


Fig. 4. DVTG-IO of a vending machine.

Now, we demonstrate that a path in the test tree obtained by the Coverage Generating Test Tree Algorithm corresponds to a timed word that is a digitization of the one timed word of the specification model describing a duration system.

Proposition 2: Let $\omega \in L(S)$ be a timed word and $[\omega]_\epsilon \in L(S')$ its digitization for $\epsilon \in [0, 1[$, if $\exists a \in Act$ and $\exists \tau' \in \mathbb{N}$ such that $[\omega]_\epsilon.a\tau' \in L(S')$ then $\forall \tau \in]\tau' - 1 + \epsilon, \tau' + \epsilon]$ we have $\omega.a\tau \in L(S)$.

The test generation from the approximate specification model can give to the tester the action and the integer time value of its execution on the IUT in discrete time. The above proposition shows that if the tester executes the action (input or output) within a

real-time interval, defined by the proposition 2, then the conformance of the observation recorded on the IUT is preserved according to the approximate model.

Proposition 3: Let $\omega = a_1\tau_1a_2\tau_2\dots a_n\tau_n$ be a timed word that corresponds to a path from the root to a leaf in T_S , then $\exists \omega' \in L(S)$ such that $[\omega']_\epsilon = \omega$

Proof: We proceed by a recursive proof on the size of ω . Let $\omega_i = a_1\tau_1a_2\tau_2\dots a_i\tau_i$ with $i \leq n$ be the timed word obtained in the level i of the test tree, we have $\omega_n = \omega$. For $i = 0$, $\omega_0 = \emptyset$ the proposition is true because $(\omega'_0 = \emptyset) \omega'_0 \in L(S)$ and we have $[\omega'_0]_\epsilon = \omega_0$.

For $i < n$, we suppose that the proposition is true for i and we try to demonstrate for $i + 1$, $\exists \omega'_i \in L(S)$ such that $[\omega'_i]_\epsilon = \omega_i$. Given $a\tau \in Out(S' \text{ after } \omega_i) \cup In(S' \text{ after } \omega_i)$, we have $\omega_i.a\tau \in L(S')$. From the proposition 2, $\forall \tau' \in]\tau - 1 + \epsilon, \tau + \epsilon]$ we have $\omega'_i.a\tau' \in L(S)$.

So $[\omega'_i.a\tau']_\epsilon = \omega_i.a\tau$.

A path in the test tree is a discrete timed word obtained from the countable state graph $(N(St_{S'}), \overset{1}{\rightsquigarrow} \cup \overset{a}{\rightsquigarrow})$ associated to the approximate model $S' = App(S)$. In proposition 3, we demonstrate that a path in the test tree corresponds to a digitization of a timed word belonging to the initial model S .

By considering this result and the result obtained in the proposition 2, we can use the test tree to generate a discrete test case, then we can experiment it by considering continuous time. For generating an input timed action that should be executed on the IUT, the tester chooses one integer timed action $a\tau$ from the test tree. By proposition 2, the action a can be applied within the real-time interval $]\tau - 1 + \epsilon, \tau + \epsilon]$.

5 Conformance Relation

5.1 Definition of the Dioco Relation

In this section we present a conformance relation to show that the generated test cases from the approximate model are sound, including those that meet the coverage criteria.

We recall the definition of the duration input output conformance relation (dioco for short) first introduced in [12] and which is in turn inspired from the untimed conformance relation (ioco) of [16].

Let S be the DVTG-IO representing the specification of a duration system and Imp be a DVTG-IO representing the implementation under test. The duration input output conformance relation, denoted dioco, is defined as :

$$Imp \text{ dioco } S \iff_{def} \forall \omega \in L(S) Out(Imp \text{ after } \omega) \subseteq Out(S \text{ after } \omega).$$

The dioco relation states that an implementation Imp conforms to its specification S if and only if for any observation ω of S , the set of observable timed output actions obtained after the application of ω on Imp must be a subset of the set of possible timed output actions obtained after the application of ω on S .

5.2 Soundness Coverage Test Cases

Soundness test cases mean that if an implementation conforms to its specification, it will pass all test cases (timed words) belonging to the set of test cases. In other words,

if the implementation fails at least one test case (timed word) then the implementation does not conform to its specification.

It is well known that soundness property is achievable for practical testing. It is shown in [3] that it is theoretically possible to produce a complete test case (i.e. soundness and exhaustiveness test cases) but in practice it is not possible to execute an infinite number of tests in a limited period of time. We prove that test cases satisfying coverage criteria and generated from the test tree are sounded by considering the conformance relation dioco.

First, let us define the digitization of the operator Out , given a digitization quantum $\varepsilon \in [0, 1[$ and for $C \subseteq C_s$ is a set of configurations.

$$[Out(C)]_\varepsilon = \{o\tau', o \in Act_{Out}, \tau' \in \mathbb{N} | \exists \tau \in \mathbb{R}^+, o\tau \in Out(C) \text{ and } [\tau]_\varepsilon = \tau'\}.$$

Proposition 4: $\forall \omega \in L(S)$, if $Out(Imp \text{ after } \omega) \subseteq Out(S \text{ after } \omega)$ then for $\varepsilon \in [0, 1[$, $[Out(Imp \text{ after } \omega)]_\varepsilon \subseteq [Out(S \text{ after } \omega)]_\varepsilon$.

Proof: Let $o\tau' \in [Out(Imp \text{ after } \omega)]_\varepsilon$. We remember the definition of the digitization of the operator Out ; $\exists \tau \in \mathbb{R}^+$, $o\tau \in Out(Imp \text{ after } \omega)$ and $[\tau]_\varepsilon = o\tau'$. From the hypothesis of this proposition we have that $o\tau \in Out(S \text{ after } \omega)$. The definition of the digitization of the operator Out ensures that $[\tau]_\varepsilon \in [Out(Imp \text{ after } \omega)]_\varepsilon$. So $o\tau' \in Out(S \text{ after } \omega)$.

Then we conclude that $[Out(Imp \text{ after } \omega)]_\varepsilon \subseteq [Out(S \text{ after } \omega)]_\varepsilon$.

We deduce from this result and proposition 3 that $Imp \text{ dioco } S \iff_{def} \forall \omega \in T, \forall \varepsilon \in [0, 1[[Out(Imp \text{ after } \omega)]_\varepsilon \subseteq [Out(S \text{ after } \omega)]_\varepsilon$.

6 Conclusions

We have introduced a method for generating test cases with respect to coverage criteria for duration systems. First, we used the DVTG-IO as a formalism to model specification. Second, we presented the approximation method. This method extends a given DVTG-IO to another called approximate model that contains the initial test cases as well as their digitizations.

Then, we proposed an algorithm that generates a set of test cases presented in a tree by considering a predefined coverage criteria. The coverage criterion, considered in this paper, is the state coverage. We demonstrated that test cases generated from the approximate model correspond to the digitization of timed words of the specification model. At the end, we showed that those test cases are sound by considering the dioco conformance relation.

In the future work, we plan to implement this algorithm with different coverage criteria and to apply this approach to other systems such as real-time systems and hybrid systems.

References

1. Alur R., Courcoubetis C., and Dill D., Model-Checking for Real-Time Systems, 5th Symp. on logic in Computer Science, 1990.
2. Alur R. and Dill D., A Theory of Timed Automata, Theoretical Computer Science, 126 : 183-235, 1994.

3. Bouajjani A., Echahed R., Robbana R., Verifying Invariance Properties of Timed Systems with Duration Variables, *Formal Techniques in Real-Time and Fault Tolerant Systems*, 1994.
4. Cassez F, Larsen K.G, The Impressive Power of Stopwatches, *Proc. Conference on Concurrency Theory CONCUR'00*, Pennsylvania, USA, 2000
5. Cerans K., Decidability of Bisimulation Equivalence for Parallel timer Processes, In *Proc. Computer Aided Verification (CAV'92)*, Springer-Verlag, 1992, LNCS 663.
6. En-Nouary A., Dssouli R., Khender F., and Elqortobi A., Timed Test cases generation based on state characterisation technique, In *RTSS'98*. IEEE, 1998.
7. Henzinger T., Manna Z., and Pnuelli A., What good are digital clocks?, In *ICALP'92*, LNCS 623, 1992.
8. Hessel A., Pettersson P., A Test Case Generation Algorithm for Real-Time Systems, In *Proc. 4th international Conference on Quality software*, pp. 268-273, 2004.
9. Krichen M, Tripakis S., Black-Box Conformance Testing for Real-Time Systems, *SPIN'04 Workshop on Model Checking Software*, 2004.
10. Majdoub L. and Robbana R., Testing Duration Systems using an Approximation Method, *Depcos-RELCOMEX*, pp.119-126, Szklarska Poreba, Poland, June 2007.
11. Majdoub L. and Robbana R., Testing Duration systems, *Journal Européen des Systèmes Automatisés*, vol 42 n°9/2008, pp. 1111-1134, November 2008.
12. Majdoub L. and Robbana R., Test cases generation for nondeterministic duration systems, *7th MSVVEIS*, pp.14-23, Milan, Italy, May 2009.
13. Robbana R, Verification of Duration Systems using an Approximation Approach, *Journal Computer Science and Technology*, Vol 18, N° 2, pp. 153-162, March 2003.
14. Springintveld J., Vaandrager F., and D'Argenio P., Testing Timed Automata, *Theoretical Computer Science*, 254, 2001.
15. Tretmans J, Testing Concurrent Systems : A Formal Approach, *CONCUR'99* , 10th Int. conference on Concurrency Theory, pages 46-65, 1999.
16. Zhu H, Hall P, May J, Software unit test coverage and adequacy, *ACM Computing Surveys*, 29(4), 1997.